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Application/Control No.	App
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Applicant(s)/Patent under Reexamination
BAKKA ET AL.

10/516,639

Art Unit

Examiner

Chau N. Nguyen

2831

	SEARCHED		
Class	Subclass	. Date	Examiner
174	113R	7/6/2005	CN
	102R		
	106R		
336	205		
	206		

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